



# FGA180N30D

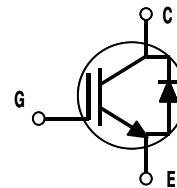
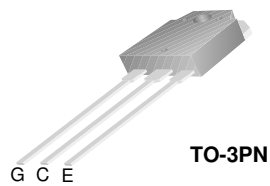
## 300V PDP IGBT

### Features

- High Current Capability
- Low saturation voltage:  $V_{CE(sat)}$ , Typ = 1.1 V@  $I_C = 40A$
- High Input Impedance

### Description

Employing Unified IGBT Technology, FGA180N30D provides low conduction and switching loss. FGA180N30D offers the optimum solution for PDP applications where low conduction loss is essential.



### Absolute Maximum Rating TC = 25oC unless otherwise noted

Symbol	Description	FGA180N30D	Units
$V_{CES}$	Collector-Emitter Voltage	300	V
$V_{GES}$	Gate-Emitter Voltage	± 30	V
$I_C$	Collector Current @ $T_C = 25^\circ C$	180	A
$I_{CM}$	Pulsed Collector Current (Note 1) @ $T_C = 25^\circ C$	450	A
$I_F$	Diode Continuous Forward Current @ $T_C = 100^\circ C$	10	A
$I_{FM}$	Diode Maximum Forward Current	40	A
$P_D$	Maximum Power Dissipation @ $T_C = 25^\circ C$	480	W
	Maximum Power Dissipation @ $T_C = 100^\circ C$	192	W
$T_J$	Operating Junction Temperature	-55 to +150	°C
$T_{stg}$	Storage Temperature Range	300	°C
$T_L$	Maximum Lead Temp. for soldering Purposes, 1/8" from case for 5 seconds	300	°C

**Notes:**

(1) Repetitive test , pulse width = 100usec , Duty = 0.2

\*  $I_{c\_pulse}$  limited by max  $T_j$

### Thermal Characteristics

Symbol	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case for IGBT	--	0.26	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case for Diode	--	1.56	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	--	40	°C/W

## Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FGA180N30D	FGA180N30D	TO-3PN	--	--	30

## Electrical Characteristics of the IGBT T<sub>C</sub> = 25°C unless otherwise noted

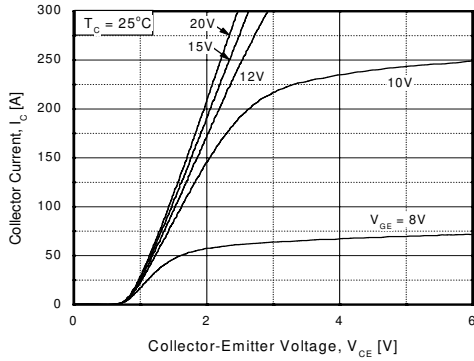
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
<b>Off Characteristics</b>						
BV <sub>CES</sub>	Collector-Emitter Breakdown Voltage	V <sub>GE</sub> = 0V, I <sub>C</sub> = 250μA	300	--	--	V
ΔBV <sub>CES</sub> / ΔT <sub>J</sub>	Temperature Coefficient of Breakdown Voltage	V <sub>GE</sub> = 0V, I <sub>C</sub> = 250μA	--	0.6	--	V/°C
I <sub>CES</sub>	Collector Cut-Off Current	V <sub>CE</sub> = V <sub>CES</sub> , V <sub>GE</sub> = 0V	--	--	100	μA
I <sub>GES</sub>	G-E Leakage Current	V <sub>GE</sub> = V <sub>GES</sub> , V <sub>CE</sub> = 0V	--	--	± 250	nA
<b>On Characteristics</b>						
V <sub>GE(th)</sub>	G-E Threshold Voltage	I <sub>C</sub> = 250μA, V <sub>CE</sub> = V <sub>GE</sub>	2.5	4.0	5.0	V
V <sub>CE(sat)</sub>	Collector to Emitter Saturation Voltage	I <sub>C</sub> = 40A, V <sub>GE</sub> = 15V	--	1.1	1.4	V
		I <sub>C</sub> = 180A, V <sub>GE</sub> = 15V, T <sub>C</sub> = 25°C	--	1.9	--	V
		I <sub>C</sub> = 180A, V <sub>GE</sub> = 15V, T <sub>C</sub> = 125°C	--	2.0	--	V
<b>Dynamic Characteristics</b>						
C <sub>ies</sub>	Input Capacitance	V <sub>CE</sub> = 30V, V <sub>GE</sub> = 0V, f = 1MHz	--	3420	--	pF
C <sub>oes</sub>	Output Capacitance		--	520	--	pF
C <sub>res</sub>	Reverse Transfer Capacitance		--	150	--	pF
<b>Switching Characteristics</b>						
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>CC</sub> = 200V, I <sub>C</sub> = 40A, R <sub>G</sub> = 5Ω, V <sub>GE</sub> = 15V, Resistive Load, T <sub>C</sub> = 25°C	--	30	--	ns
t <sub>r</sub>	Rise Time		--	210	--	ns
t <sub>d(off)</sub>	Turn-Off Delay Time		--	100	--	ns
t <sub>f</sub>	Fall Time		--	140	300	ns
E <sub>on</sub>	Turn-On Switching Loss		--	0.26	--	mJ
E <sub>off</sub>	Turn-Off Switching Loss		--	0.75	--	mJ
E <sub>ts</sub>	Total Switching Loss		--	1.01	--	mJ
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>CC</sub> = 200V, I <sub>C</sub> = 40A, R <sub>G</sub> = 5Ω, V <sub>GE</sub> = 15V, Resistive Load, T <sub>C</sub> = 125°C	--	30	--	ns
t <sub>r</sub>	Rise Time		--	230	--	ns
t <sub>d(off)</sub>	Turn-Off Delay Time		--	110	--	ns
t <sub>f</sub>	Fall Time		--	220	--	ns
E <sub>on</sub>	Turn-On Switching Loss		--	0.27	--	mJ
E <sub>off</sub>	Turn-Off Switching Loss		--	1.0	--	mJ
E <sub>ts</sub>	Total Switching Loss		--	1.27	--	mJ
Q <sub>g</sub>	Total Gate Charge	V <sub>CE</sub> = 200V, I <sub>C</sub> = 40A, V <sub>GE</sub> = 15V	--	185	277	nC
Q <sub>ge</sub>	Gate-Emitter Charge		--	24	36	nC
Q <sub>gc</sub>	Gate-Collector Charge		--	88	132	nC

**Electrical Characteristics of DIODE**  $T_C = 25^\circ\text{C}$  unless otherwise noted

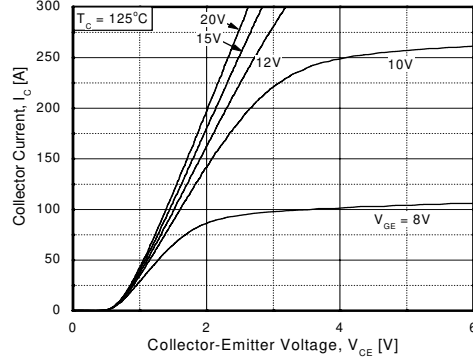
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units	
$V_{FM}$	Diode Forward Voltage	$I_F = 10\text{A}$	$T_C = 25^\circ\text{C}$	--	1.1	1.4	V
			$T_C = 125^\circ\text{C}$	--	0.9	--	
$t_{rr}$	Diode Reverse Recovery Time	$I_F = 10\text{A}$ $di/dt = 200\text{A}/\mu\text{s}$	$T_C = 25^\circ\text{C}$	--	21	--	ns
			$T_C = 125^\circ\text{C}$	--	35	--	
$I_{rr}$	Diode Peak Reverse Recovery Current		$T_C = 25^\circ\text{C}$	--	2.8	--	A
			$T_C = 125^\circ\text{C}$	--	5.6	--	
$Q_{rr}$	Diode Reverse Recovery Charge		$T_C = 25^\circ\text{C}$	--	29.4	--	nC
			$T_C = 125^\circ\text{C}$	--	98	--	

**Typical Performance Characteristics Typical Saturation Voltage Characteristics**

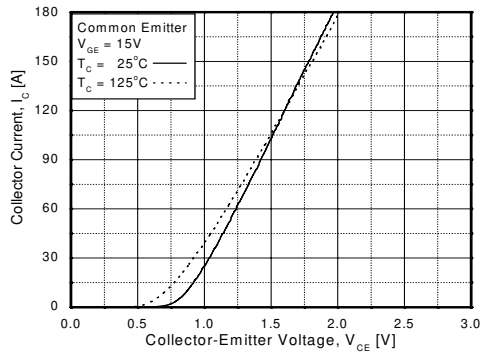
**Figure 1. Typical Output Characteristics**



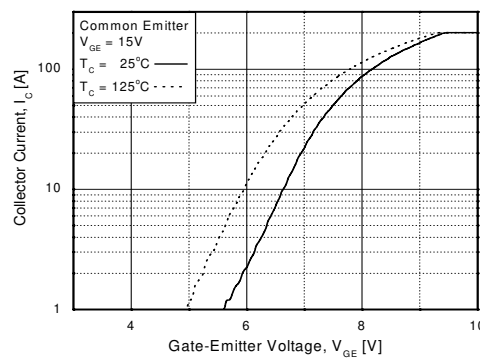
**Figure 2. Typical Output Characteristics**



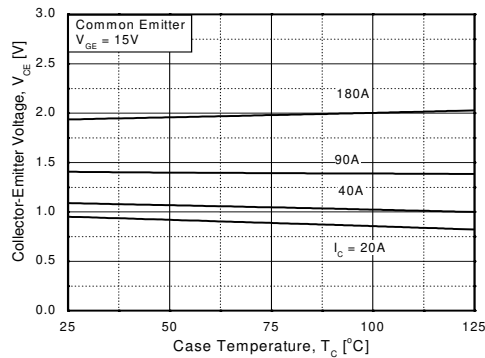
**Figure 3. Saturation Voltage**



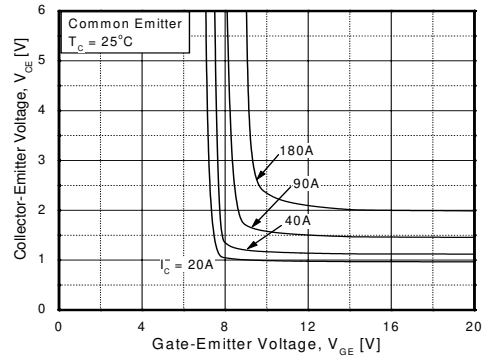
**Figure 4. Transfer Characteristics**



**Figure 5. Saturation Voltage vs. Case Temperature at Variant Current Level**

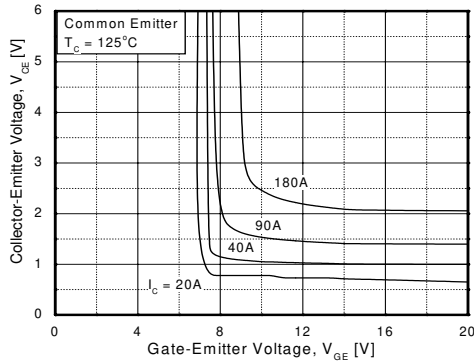


**Figure 6. Saturation Voltage vs.  $V_{GE}$**

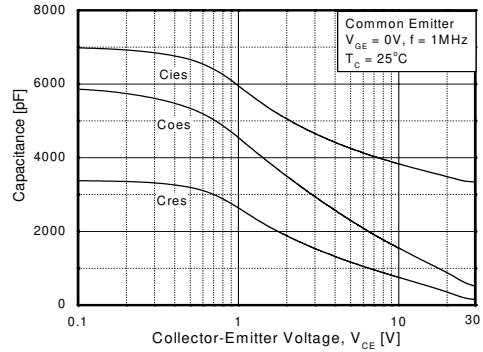


**Typical Performance Characteristics (Continued)**

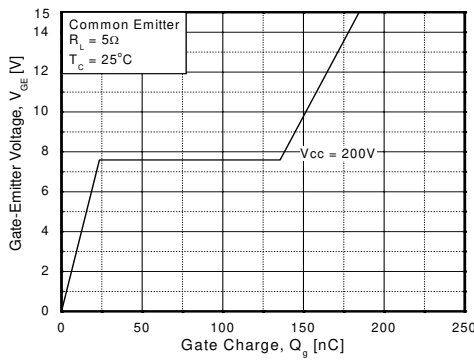
**Figure 7. Saturation Voltage vs.  $V_{GE}$**



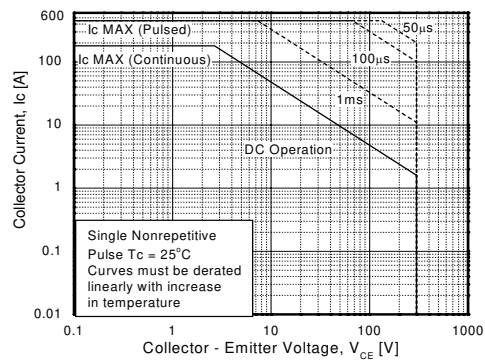
**Figure 8. Capacitance Characteristics**



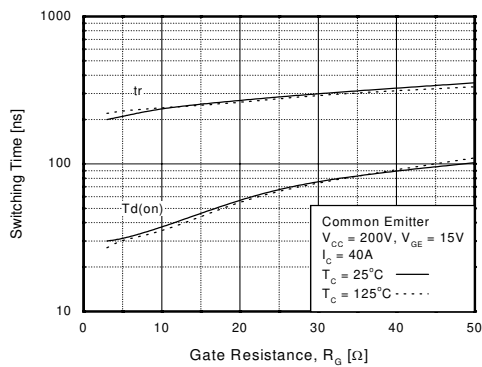
**Figure 9. Gate Charge Characteristics**



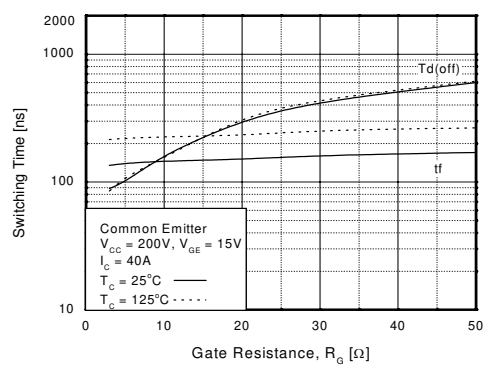
**Figure 10. SOA Characteristics**



**Figure 11. Turn-On Characteristics vs. Gate Resistance**

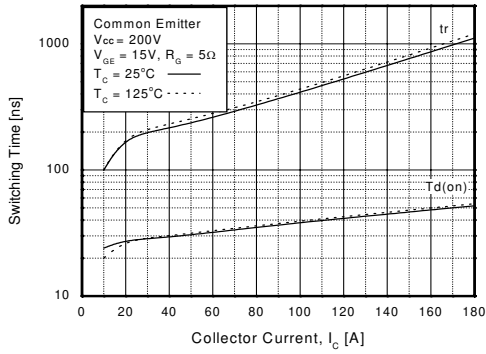


**Figure 12. Turn Off Characteristics vs. Gate Resistance**

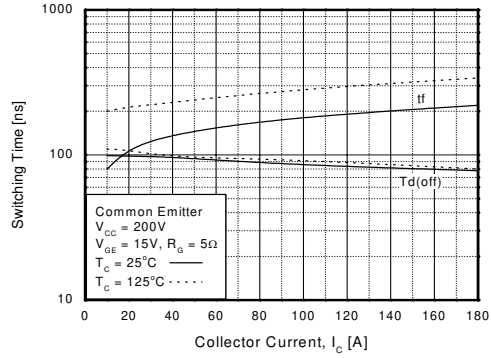


**Typical Performance Characteristics** (Continued)

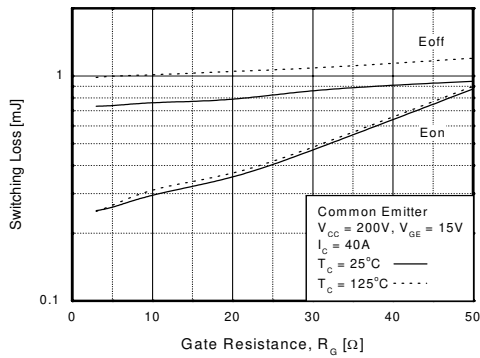
**Figure 13. Turn-On Characteristics vs. Collector Current**



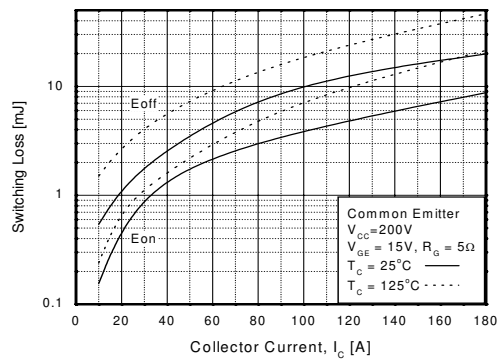
**Figure 14. Turn-Off Characteristics vs. Collector Current**



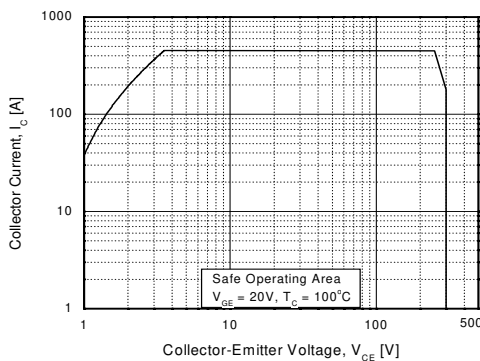
**Figure 15. Switching Loss vs Gate Resistance**



**Figure 16. Switching Loss vs Collector Current**

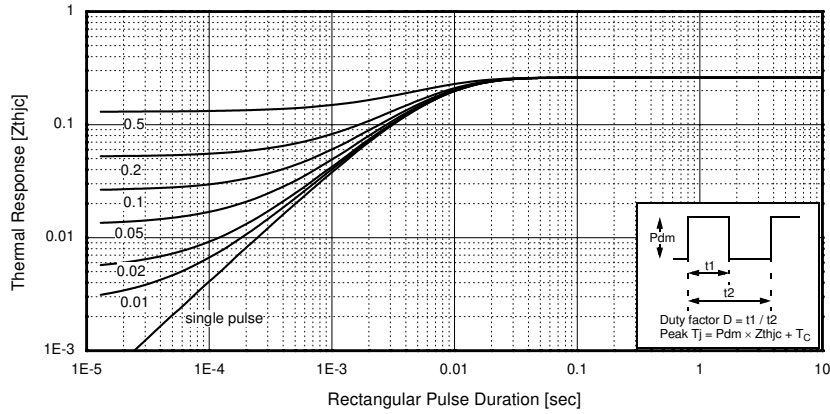


**Figure 17. Turn Off SOA Characteristics**

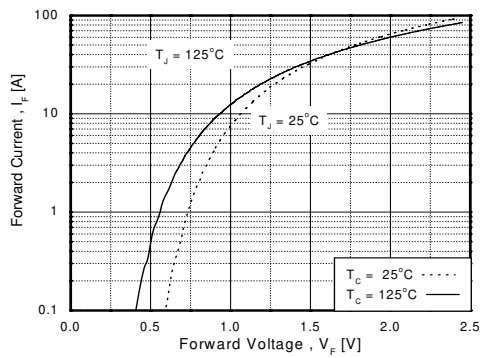


**Typical Performance Characteristics (Continued)**

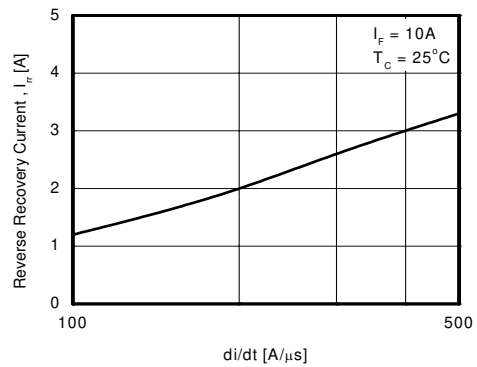
**Figure 18. Transient Thermal Impedance of IGBT**



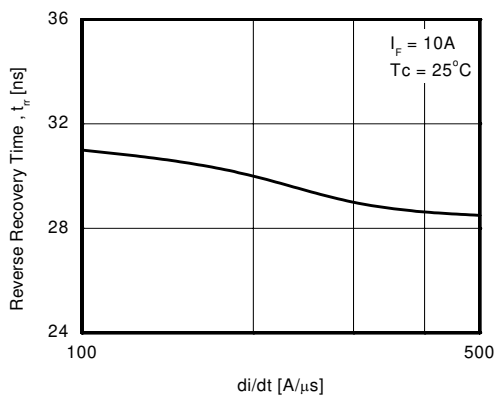
**Figure 19. Forward Characteristics**



**Figure 20. Typical Reverse Recovery Current**

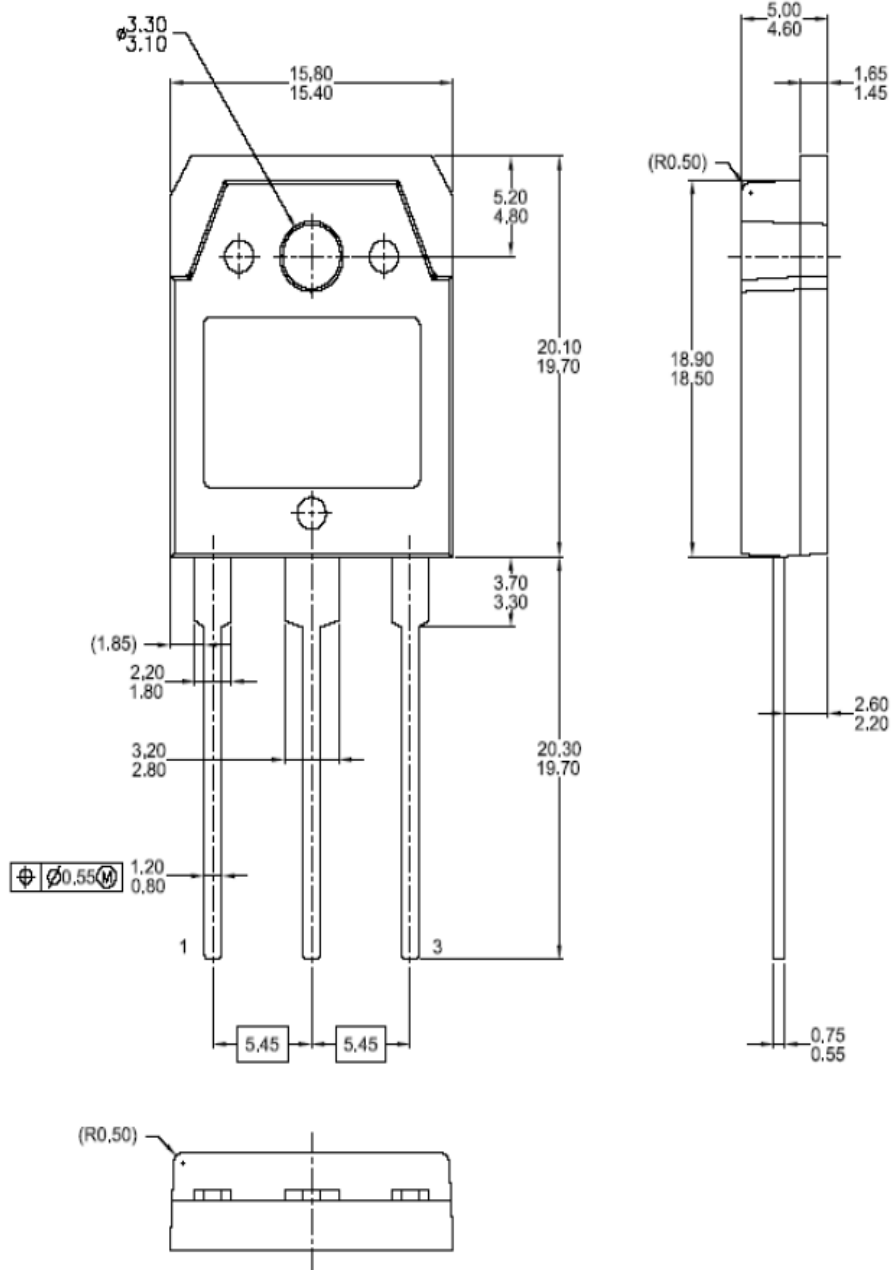


**Figure 21. Typical Reverse Recovery Time**



Mechanical Dimensions

TO-3PN



Dimensions in Millimeters



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CROSSVOLT™	GTO™	MICROWIRE™	QT Optoelectronics™	TCM™
DOME™	HiSeC™	MSX™	Quiet Series™	TinyLogic®
EcoSPARK™	I <sup>2</sup> C™	MSXPro™	RapidConfigure™	TINYOPTO™
E <sup>2</sup> CMOS™	i-Lo™	OCX™	RapidConnect™	TruTranslation™
EnSigna™	ImpliedDisconnect™	OCXPro™	μSerDes™	UHC™
FACT™	IntelliMAX™	OPTOLOGIC®	ScalarPump™	UniFET™
FACT Quiet Series™		OPTOPLANAR™	SILENT SWITCHER®	UltraFET®
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